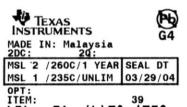
PCN Number:		20150625002					PCN Dat	<b>PCN Date:</b> 06/30/2						
I ITIE'		Qualifica Devices	ration of JCAP China as an alternate Bump, Assembly, and Test Site for select WCSP											
Cust	ome	r Contac	t:				PCI	N Manager	Dept:		Qualit	uality Services		
Proposed 1 <sup>st</sup> Ship Date:				09/30/2015				Estimated Sample Availa			bility: Date provided upon request		-	
Chai	nge 1	Гуре:												
$\boxtimes$	Asse	embly Site	9	Assembly Process				As	Assembly Materials					
	Des	ign				Electrical Specification				Me	Mechanical Specification			
	Test	Site				Packing/Shipping/Labeling				Te	Test Process			
		er Bump :				Wafer Bump Material				Wa	Wafer Bump Process			
Wafer Fab Site		<u>L</u>		Wafer Fab Materials			ļL	Wa	Wafer Fab Process					
Part number change														
PCN Details														
Description of Change:														
Texas Instruments is pleased to announce the qualification of JCAP China as an alternate Bump, Assembly, and Test site for the devices shown below. The material set will be the same between the 2 sites.  Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.														
Reason for Change:														
Continuity of Supply														
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):														
None														

## Changes to product identification resulting from this PCN:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (21L)	Assembly City
TI Clark	QAB	PHL	Angeles City, Pampanga
JCAP	JCP	CHN	Jiangsu

Sample product shipping label (not actual product label)



LBL: 5A (L)TO:3750



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812 (P) (2P) REV: (V) 0033317 (20L) C\$0: \$HE (21L) CCO:U\$A (22L) A\$0: MLA (23L) ACO: MY\$

**Topside Device marking:** 

Assembly site code for QAB= I

Assembly site code for JCP= P

Product Affected								
	1							
TPS65132A0YFFR	TPS65132AYFFR	TPS65132B0YFFR	TPS65132BYFFR					
		•	•	-				



TI Information Selective Disclosure

## **Qualification Report**

TPS65132BYFFR, TPS65132B0YFFR, TPS65132AYFFR & TPS65132A0YFFR JCAP Multi-Source 2nd Site Approve Date 27-May-2015

## Product Attributes

Attributes	Qual Device: TPS65132B0YFF	Qual Device: TPS65132AYFF	QBS Package Reference: DRV2604YZF	QBS Package Reference: CD3230A0YFF
Assembly Site	JCAP	JCAP	JCAP	JCAP
Package Family	WCSP	WCSP	WCSP	WCSP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	RFAB	RFAB	RFAB	RFAB
Wafer Process	LBC7	LBC7	LBC8LV	LBC7

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TPS65132B0YFF	Qual Device: TPS65132AYFF	QBS Package Reference: DRV2604YZF	QBS Package Reference: CD3230A0YFF
ED	ElectricalCharacterization	Per Datasheet Parameters	Pass	Pass		
HAST	Biased HAST, 130C/85%RH	96 Hours			3/231/0	1/77/0
HBM	ESD - HBM	4000 V			3/9/0	
CDM	ESD - CDM	1500 V			3/9/0	
HTOL	Life Test, 125C	1000 Hours				1/80/0
HTOL	Life Test, 140C	480 Hours			3/231/0	
HTOL	Life Test, 150C	300 Hours				
HTSL	High Temp. Storage Bake, 170C	420 Hours			3/135/0	3/231/0
LU	Latch-up	(per JESD78)			3/18/0	
PD	Physical Dimensions				3/60/0	3/15/0
SBS	Bump-shear	Solder Bumps			3/135/0	3/150/0
TC	Temperature Cycle, -55/125C	700 Cycles			3/231/0	
UHAST	Unbiased HAST 130C/85%RH	96 Hours				3/231/0

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

<sup>-</sup>QBS: Qual By,Similarity
-Qual Devices qualified at LEVEL1-260C: TPS65132A0YFF, TPS65132AYFF
-Qual Devices qualified at LEVEL1-260CG: TPS65132B0YFF, TPS65132BYFFR

<sup>-</sup> The following are equivalent HTOL options based on an activation energy of Q\_TeX\_125C/1X hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of Q\_TeX\_150C/1X Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESQ4T\_55C/125C/700 Cycles and -65C/150C/500 Cycles